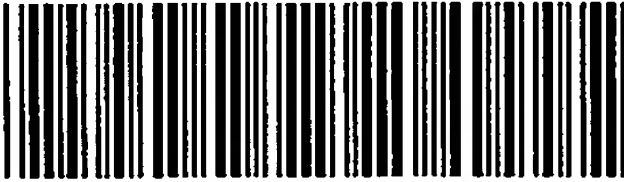


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/071,368	HASEGAWA ET AL.	
	Examiner	Art Unit	
	TUYEN T. NGUYEN	2832	

SEARCHED			
Class	Subclass	Date	Examiner
336	210-213, 233, 234	2/16/2005	TTN
148	304-306	2/16/2005	TTN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR